

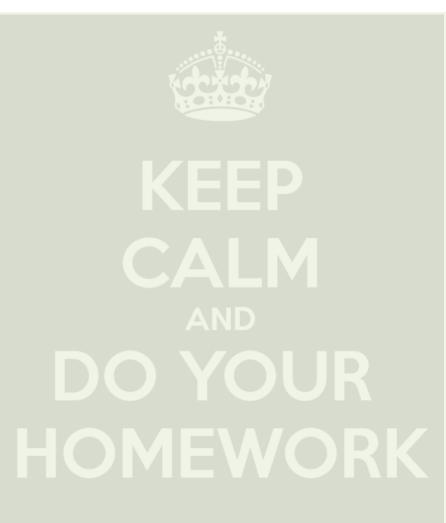
Fall 2021 Lab 4: Finite State Machines

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Agenda

- Lab 4 Outline
- Lab 4 Basic Questions
- Lab 4 Advanced Questions



Lab 4 Outline

- Basic questions (1.5%)
 - Individual assignment
 - Due on 11/2/2021 (Thu). In class.
- Advanced questions (5%)
 - Group assignment
 - Demonstration on your FPGA board (In class)
 - Lab report should be submitted using PDF format
 - Assignment submission (Submit to EEClass)
 - EEClass submission (code, test bench, and report) due on 11/11/2021 (Thu) 23:59:59 for the Advanced Questions.
 - EEClass submission (code and report) due on 11/18/2021 (Thu)
 23:59:59 for the FPGA Question

Lab 4 Rules

- Please note that grading will be based on NCVerilog
- You can use ANY modeling techniques
- If not specifically mentioned, we assume the following SPEC
 - clk is positive edge triggered
 - Synchronously reset the Flip-Flops when rst_n == 1'b0, if there exists one rst_n signal in the specification

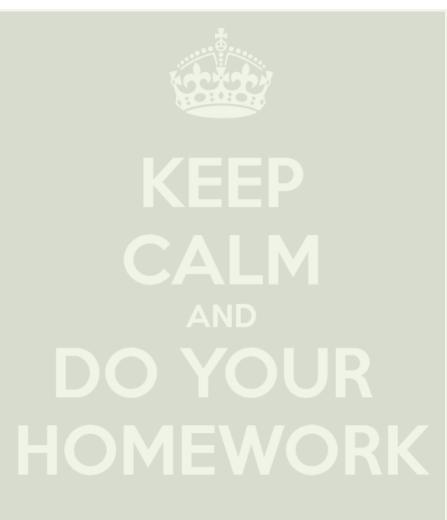
Lab 4 Submission Requirements

Source codes and testbenches

- Please follow the templates EXACTLY
- We will test your codes by TAs' testbenches
- Lab 4 report
 - Please submit your report in a single PDF file
 - Please draw the block diagrams and state transition diagrams of your designs
 - Please explain your designs in detail
 - Please list the contributions of each team member clearly
 - Please explain how you test your design
 - What you have learned from Lab 4

Agenda

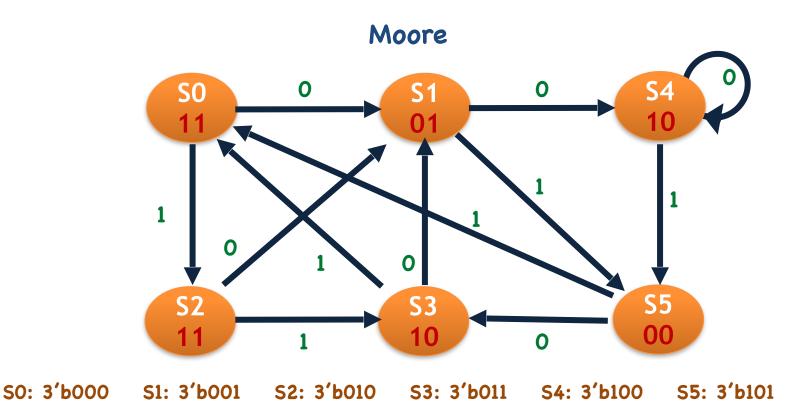
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- Lab 4 Advanced Questions



Basic Questions

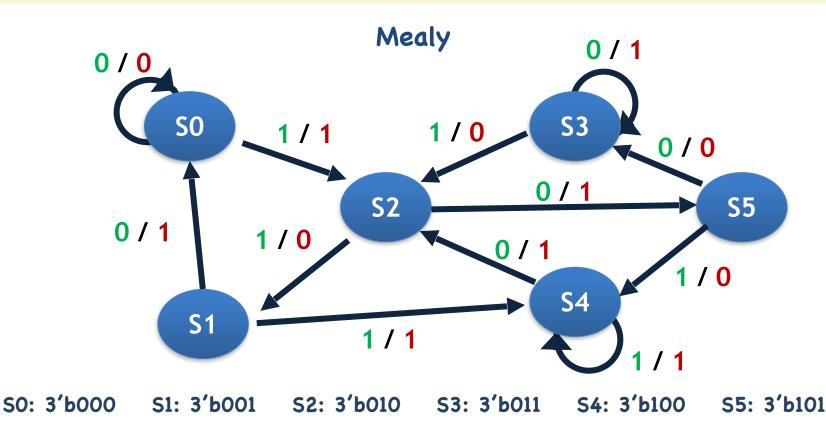
- Individual assignment
 - Verilog questions (due on 11/2/2021. In class.)
 - Moore machine
 - Mealy machine
 - Many-to-one linear-feedback shift register
 - One-to-many linear-feedback shift register
 - Demonstrate your work by waveforms

- Moore machine
 - **Green** represents input, while **red** represents output
 - Output your current state as well
 - When **rst_n** == 1′b0, **state** = S0

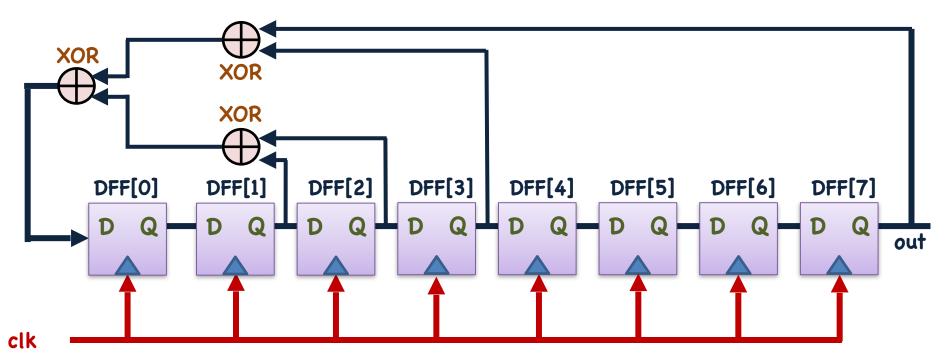


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- Mealy machine
- Green represents input, while red represents output
- Output your current state as well
- When **rst_n** == 1′b0, **state** = S0

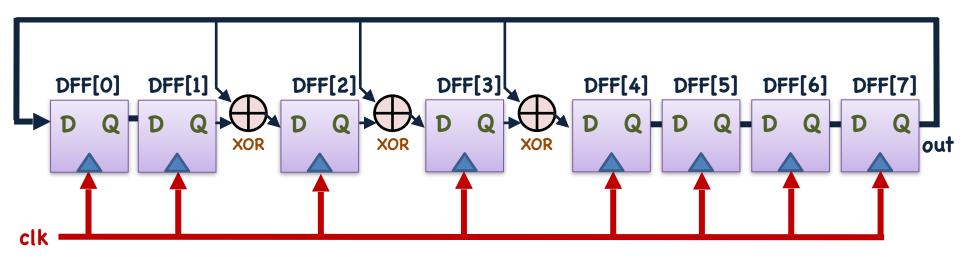


Many-to-one linear-feedback shift register (LFSR)



- When rst_n == 1'b0, reset DFF[7:0] to 8'b10111101
- Please draw the state transition diagram of the DFFs in LFSR for the first ten states after rst_n is raised to 1'b1 in your report
- Please describe what happens if we reset the DFFs to 8'd0 in your report

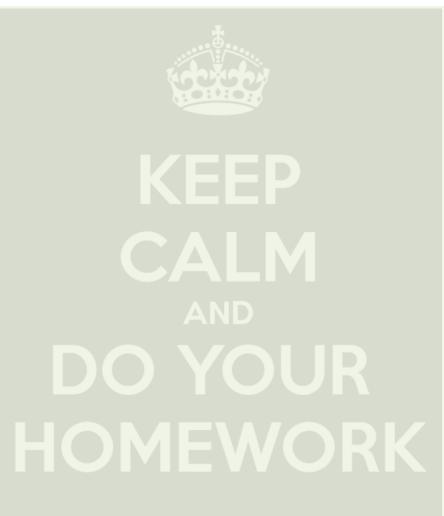
One-to-many linear-feedback shift register (LFSR)



- When **RESET == 1'b0**, reset DFF[7:0] to **8'b10111101**
- Please draw the state transition diagram of the DFFs in LFSR for the first ten states after rst_n is raised to 1'b1 in your report
- Please describe what happens if we reset the DFFs to **8'd0** in your report

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- Lab 4 Advanced Questions



Advanced Questions

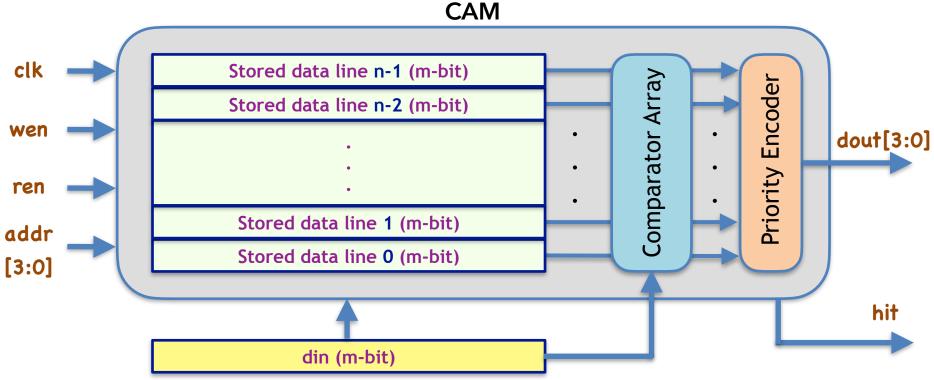
Group assignment

- Verilog questions
 - Source codes and the report due on 11/11/2021. 23:59:59.
 - Content-addressable memory (CAM) design
 - Scan chain design
 - Built-in self test
 - Mealy machine sequence detector
- FPGA demonstration (due on 11/18/2021. In class.)
 - 1A2B game

Verilog Advanced Question 1

Content-addressable memory (CAM) design

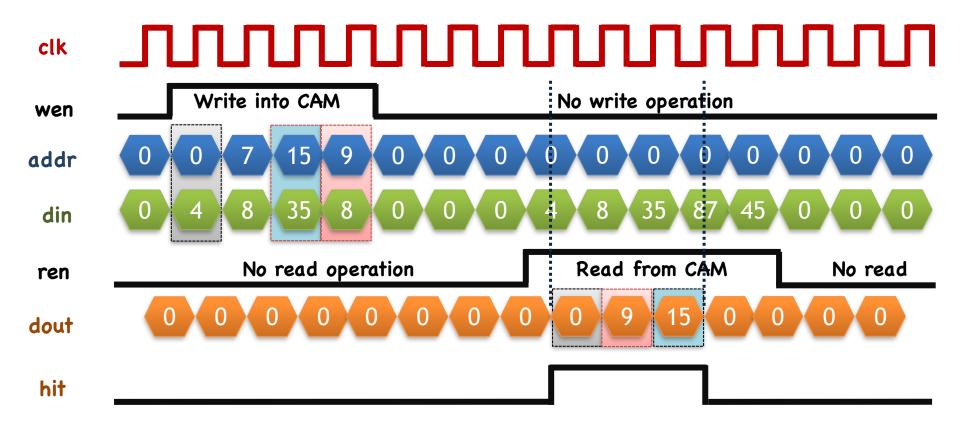
- Design a CAM that stores n sets of m-bit data lines (n = 16, m = 8)
- Input: clk, wen, ren, addr[3:0], din[m-1:0]
- Output: dout[3:0], hit



Verilog Advanced Question 1 (Con't)

- When wen == 1'b1, write din to CAM[addr]
- When **ren == 1'b1**:
 - If there is only one matching data in the CAM, set **dout** to the matching data's address and set **hit** to **1'b1**
 - If there are multiple matches in the CAM, set dout to the largest address among them and set hit to 1'b1.
 - If there is no match in the CAM, set **dout** to **1'b0** and set **hit** to **1'b0**
- When both wen and ren are 1'b1, perform read operation only and ignore the write request
- When both ren and wen are 1b'0, set **dout** to 1'b0 and set **hit** to 1'b0
- Please refer to the next page for example waveform

Verilog Advanced Question 1 (Con't)

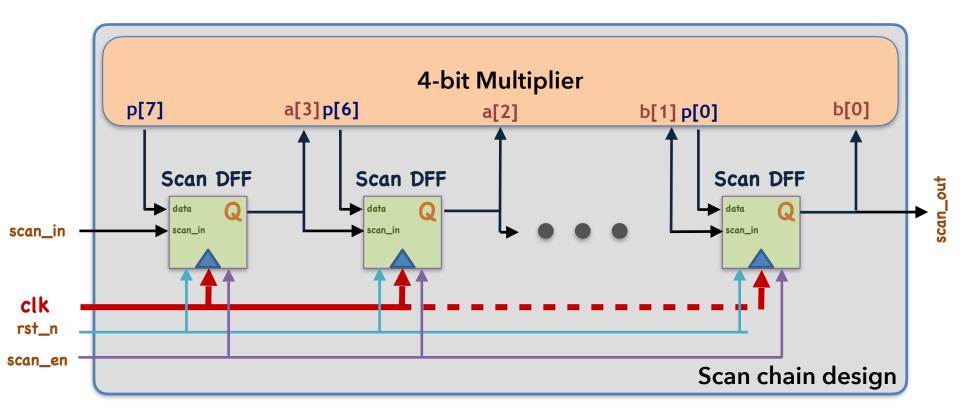


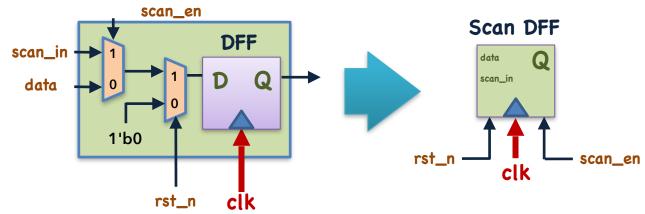
Verilog Advanced Question 2

Scan chain design

- Scan chain is a technique used in design for testing. The objective is to make testing easier by providing a simple way to set and observe every flip-flop in a circuit. The structure of a scan chain is illustrated in the next page.
 - In order to achieve the above objective, the DFFs in a circuits are all replaced by a special type of DFF, called scan DFF (SDFF), which is also shown in the next page. An SDFF contains several extra ports: scan_in and scan_en, and is larger than the original DFF.
 - All the SDFFs are connected in a chain, which is called a scan chain.
- In this question, you are required to design a scan chain for a 4-bit multiplier, which is a combinational circuit and can be designed by any modeling technique.
 - Input: clk, rst_n, scan_in, scan_en
 - Output: scan_out
- Reset all SDFFs to **1′b0** when **rst_n** == 1′b0

Verilog Advanced Question 2 (Con't)



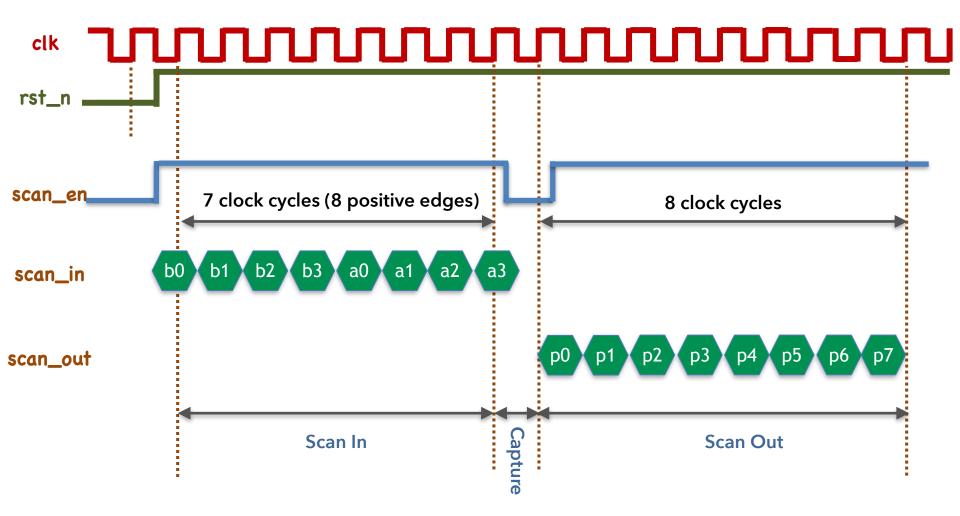


Verilog Advanced Question 2 (Con't)

The behavior of a scan chain

- The behavior of a scan chain contains three phases: **scan in**, **capture**, and **scan out**.
 - Scan in
 - In this phase, **scan_en** is set to **1'b1**, and a test pattern is scanned (shifted) from the **scan_in** port into the scan chain bit-by-bit.
 - Capture
 - In this phase, **scan_en** is set to **1'b0**, and the circuit performs its original functionality.
 - The inputs of the multiplier is provided by the values stored in SDFF. The output of the multiplier is stored back to the SDFFs at the positive clock edge.
 - Scan out
 - In this phase, **scan_en** is set to **1'b1** again, and the values stored in the SDFFs are shifted to the **scan_out** port of the scan chain bit-by-bit.
- In TA's test bench, the scan_en signal is controlled according to this three-phase behavior pattern to test your scan chain design.
- Please refer to the next page for the example behavior waveform.

Verilog Advanced Question 2 (Con't)

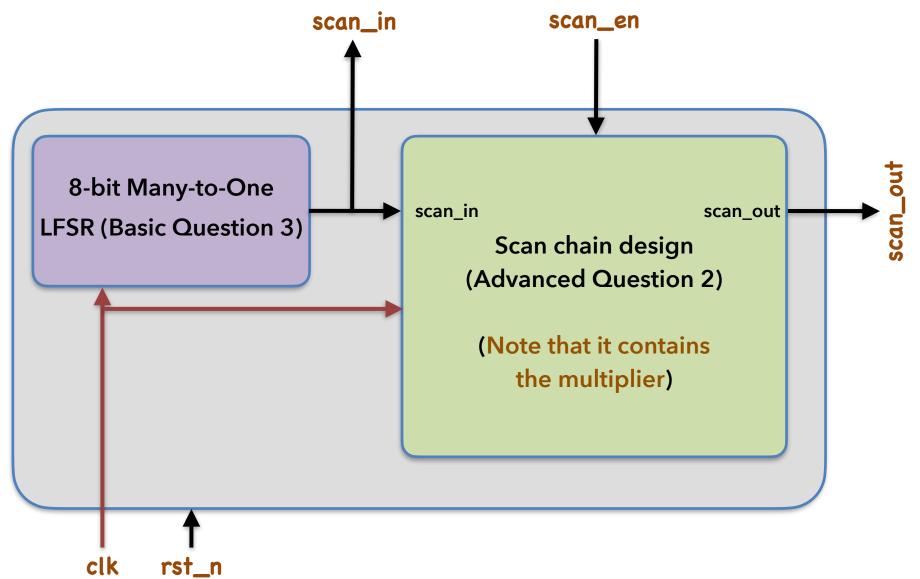


Verilog Advanced Question 3

Built-in self test (BIST)

- In the previous question, we designed a scan chain. Now we add a test pattern generator in front of it. The test pattern generator is implemented by a 8-bit many-to-one LFSR, which is the same as the design in the basic question 3. Since the test pattern generator is inside a chip, this architecture is called "built-in self test (BIST)".
 - Please reuse the scan chain from the advanced question 2
- Please modify your LFSR from the basic question 3 so that only the MSB of the LFSR is shifted into the scan chain.
- Typically, a circuit with BIST does not have scan_in and scan_out ports. However, for the grading purposes, the two ports are set as output ports, so as to allow them to be observable.
 - Input: **clk**, **rst_n**, **scan_en**
 - Output: **scan_in**, **scan_out**

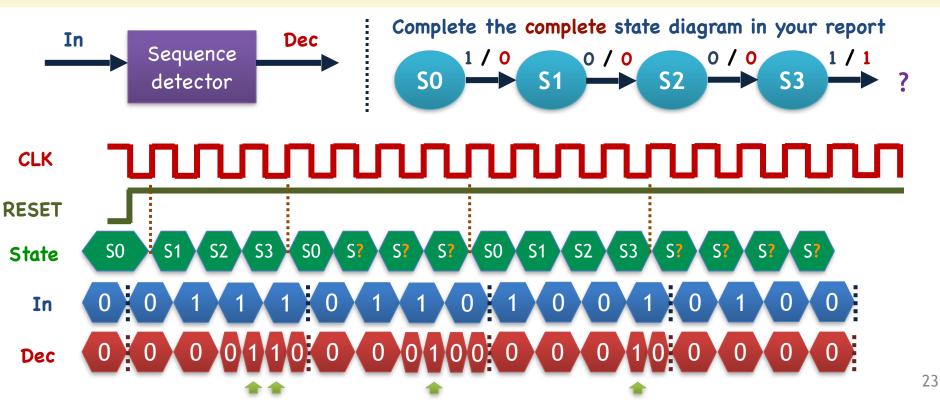
Verilog Advanced Question 3 (Con't)



Verilog Advanced Question 4

Mealy machine sequence detector

- 1-bit input In and 1-bit output Dec
- When the four bit sequence is 0111, 1001, or 1110, Dec is set to 1
- Re-detect the sequence every four bits
- Please draw your state diagram in your report



Advanced Questions

- Group assignment
- Verilog questions
 - Source codes and the report due on 11/11/2021. 23:59:59.
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 - 1A2B game

FPGA Demonstration

The 1A2B game

Traditionally, this is a two-player code-breaking game. However, in this lab, we modify it to a single-player game

The rule

- In the beginning of each game, the FPGA generates a random number consisting of four non-repeating digits, where each digit ranges from 0 to 9
- The player's task is to guess this number using the hints given by the FPGA
- The behavior of this game contains two phases: the initial phase and the guessing phase

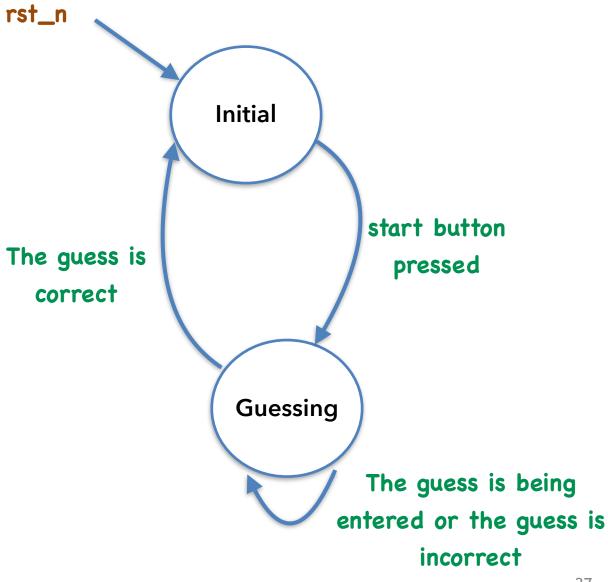
The initial phase

- When the **reset button** is pressed, reset the game to this phase
- In this phase, the seven-segment display shows "1A2b", and wait for the player to push the **start button**
- After pressing the start button, a random non-repeating 4 digit answer is generated and displayed using the LEDs, where LED[15:12] represents the first digit, LED[11:8] represent the second digit, and so on 25

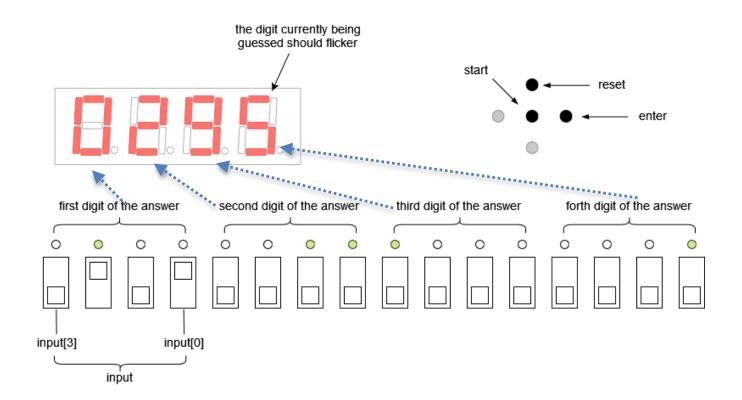
The guessing phase

- The LEDs should continue displaying the generated answer
- The player is required to guess this number one by one, from the MSB to the LSB using the leftmost 4 switches (i.e., SW[15:12]). The digit that is being guessed will flicker until the player enters his/her guess using the **enter button**
- After all the 4 digits have been entered, the seven segment display should show XAYb according the correctness of the player's guess, where X is the number of the digits with correct digit positions, and Y is number of the correct digits that are out of place.
- If the player's guess matches the answer, return the game to the initial phase after the enter button is pressed (remember to clear all the LEDs!)
- If the player's guess does not match the answer, return to this guessing phase and guess again after the enter button is pressed
- Please note that the answer of each game should be random and generated using the LFRS, which should keep operating and is only sampled when the start button is pressed
- Please refer to the demonstration video from the TAs
- Please refer to the next page for the state transition diagram

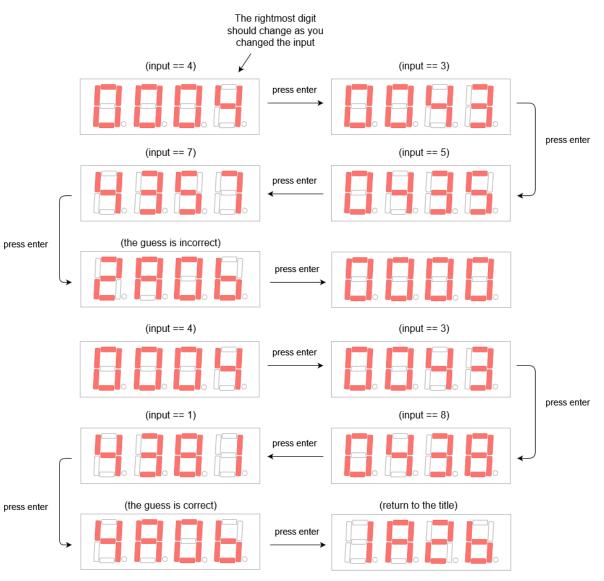
An example of the state transition diagram



- The layout of the switches, the buttons, and the seven segment display
- The real answer in the following example is 4381, as indicated by the LED pattern



- An example of the behavior of the 1A2B game (the answer in this example 4381)
- Video demonstration link: <u>shorturl.at/iuvJ3</u>
- Please note that we will note intentionally input patterns with:
 - Repeating digits
 - Digits with values
 larger than 9



u for your attention!

SMOKING

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*The first Starbucks at Seattle, Washington, USA This picture is taken by Chun-Yi Lee himself, who is also a

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ETARBU